Message from the Guest Editor

Dear Colleagues,

This special issue will focus on recent advances in the field of materials science and engineering facilitated by the use of scanning probe microscopy (SPM) instrumentation and methodologies. Example of topics within the scope of this issue include; studies of the nanoelectronic and magnetic properties of materials, nanoscale dynamic mechanical properties of materials, single cell mechanics and mechanotransduction, integration of SPM with chemical characterization techniques, atomic manipulation, high resolution imaging of biological materials and engineered tissues, nanoscale tribology, friction, lubrication, wear, nanoscale adhesion, atomic force microscope-based nanoindentation, single molecule force spectroscopy, and spatially specific nanomechanics.

Dr. Christine Ortiz
Guest Editor

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